

# MSKSEMI 美森科

SEMICONDUCTOR



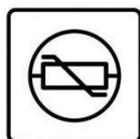
ESD



TVS



TSS



MOV



GDT



PLED

## **MS13N50P/F**

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### Product specification

## Description

The MS13N50P/F can be used in various power switching circuit for system miniaturization and higher efficiency. The package form is TO-220/ TO-220F, which accords with the RoHS standard

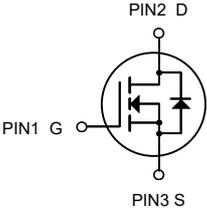
## General Features

- $V_{DS}=500V, I_D=13A$
- $R_{DS(ON)} < 0.48\Omega @ V_{GS}=10V$

## Application

- Power switch circuit of adaptor and charger

## Reference News

PACKAGE OUTLINE		P-Channel MOSFET	Marking	
				
TO-220	TO-220F		MS13N50P	MS13N50F

Note : \*\*\*\*Representative production cycle

## Absolute Maximum Ratings@T<sub>j</sub>=25°C (unless otherwise specified)

Symbol	Parameter	13N50P	13N50F	Unit
V <sub>DSS</sub>	Drain-to-Source Voltage	500		V
V <sub>GSS</sub>	Gate-to-Source Voltage	±30		
I <sub>D</sub>	Continuous Drain Current	13		A
I <sub>DM</sub>	Pulsed Drain Current at V <sub>GS</sub> =10V	52		
E <sub>AS</sub>	Single Pulse Avalanche Energy	900		mJ
P <sub>D</sub>	Power Dissipation	195	48	W
	Derating Factor above 25°C	1.56	0.38	W/°C
T <sub>L</sub> T <sub>PAK</sub>	Maximum Temperature for Soldering Leads at 0.063in (1.6mm) from Case for 10 seconds, Package Body for 10 seconds	300 260		°C
T <sub>J</sub> & T <sub>STG</sub>	Operating and Storage Temperature Range	-55 to 150		
R <sub>θJC</sub>	Thermal Resistance, Junction-to-Case	0.64	2.6	°C/W
R <sub>θJA</sub>	Thermal Resistance, Junction-to-Ambient	62	100	

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" may cause permanent damage to the device.

**Electrical Characteristics**  $T_J = 25^\circ\text{C}$  unless otherwise specified

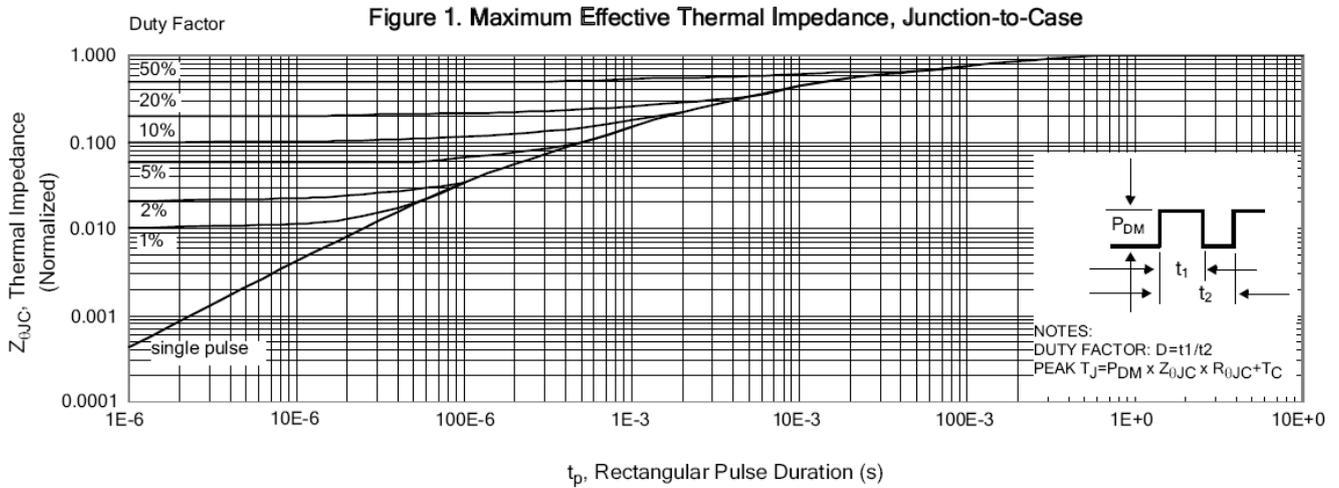
Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$BV_{DSS}$	Drain-to-Source Breakdown Voltage	500	--	--	V	$V_{GS}=0V, I_D=250\mu A$
$I_{DSS}$	Drain-to-Source Leakage Current	--	--	1	$\mu A$	$V_{DS}=500V, V_{GS}=0V$
		--	--	100		$V_{DS}=400V, V_{GS}=0V,$ $T_J = 125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Leakage Current	--	--	+100	$nA$	$V_{GS}=30V, V_{DS}=0V$
		--	--	-100		$V_{GS}=-30V, V_{DS}=0V$
$R_{DS(ON)}$	Static Drain-to-Source On-Resistance	--	0.40	0.48	$\Omega$	$V_{GS}=10V, I_D=6.5A$
$V_{GS(TH)}$	Gate Threshold Voltage	2.0	--	4.0	V	$V_{DS}=V_{GS}, I_D=250\mu A$
$g_{fs}$	Forward Transconductance	--	15	--	S	$V_{DS}=30V, I_D=13A$
$C_{iss}$	Input Capacitance	--	2150	--	$pF$	$V_{GS}=0V,$ $V_{DS}=25V,$ $f=1.0MHz$
$C_{rss}$	Reverse Transfer Capacitance	--	23	--		
$C_{oss}$	Output Capacitance	--	210	--		
$Q_g$	Total Gate Charge	--	45	--	$nC$	$V_{DD}=250V,$ $I_D=13A, V_{GS}=0$ to 10V
$Q_{gs}$	Gate-to-Source Charge	--	10	--		
$Q_{gd}$	Gate-to-Drain (Miller) Charge	--	18	--		
$t_{d(ON)}$	Turn-on Delay Time	--	15	--	$ns$	$V_{DD}=250V,$ $I_D=13A,$ $V_{GS}=10V$ $R_g=6.1 \Omega$
$t_{rise}$	Rise Time	--	25	--		
$t_{d(OFF)}$	Turn-Off Delay Time	--	45	--		
$t_{fall}$	Fall Time	--	35	--		
$I_{SD}$	Continuous Source Current <sup>[2]</sup>	--	--	13	A	Integral pn-diode in MOSFET
$I_{SM}$	Pulsed Source Current <sup>[2]</sup>	--	--	52		
$V_{SD}$	Diode Forward Voltage	--	--	1.5	V	$I_S=13A, V_{GS}=0V$
$t_{rr}$	Reverse Recovery Time	--	--	--	ns	$V_{GS}=0V$
$Q_{rr}$	Reverse Recovery Charge	--	4.0	--	$\mu C$	$I_F=13A, di/dt=100A/\mu s$

**Note:**

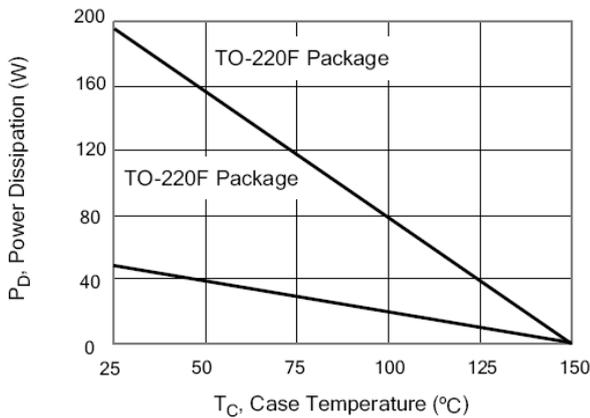
 [1]  $T_J = +25^\circ\text{C}$  to  $+150^\circ\text{C}$ 

 [2] Pulse width  $\leq 380\mu s$ ; duty cycle  $\leq 2\%$ .

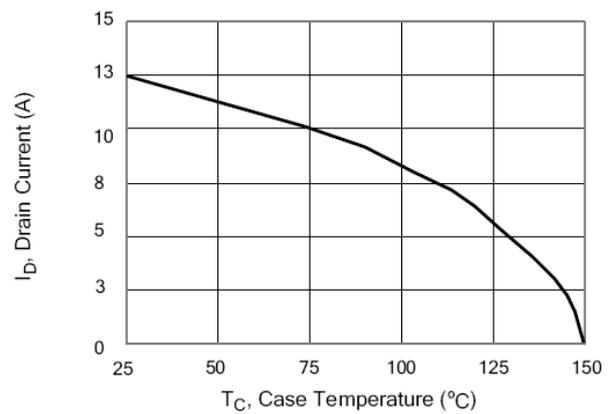
**Typical Characteristics(Cont.)**



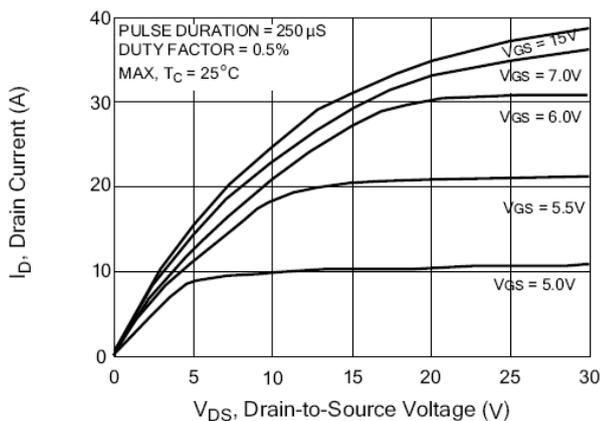
**Figure 2. Maximum Power Dissipation vs Case Temperature**



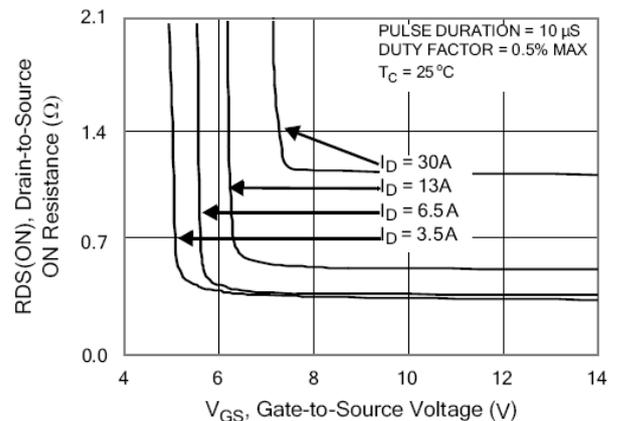
**Figure 3. Maximum Continuous Drain Current vs Case Temperature**



**Figure 4. Typical Output Characteristics**

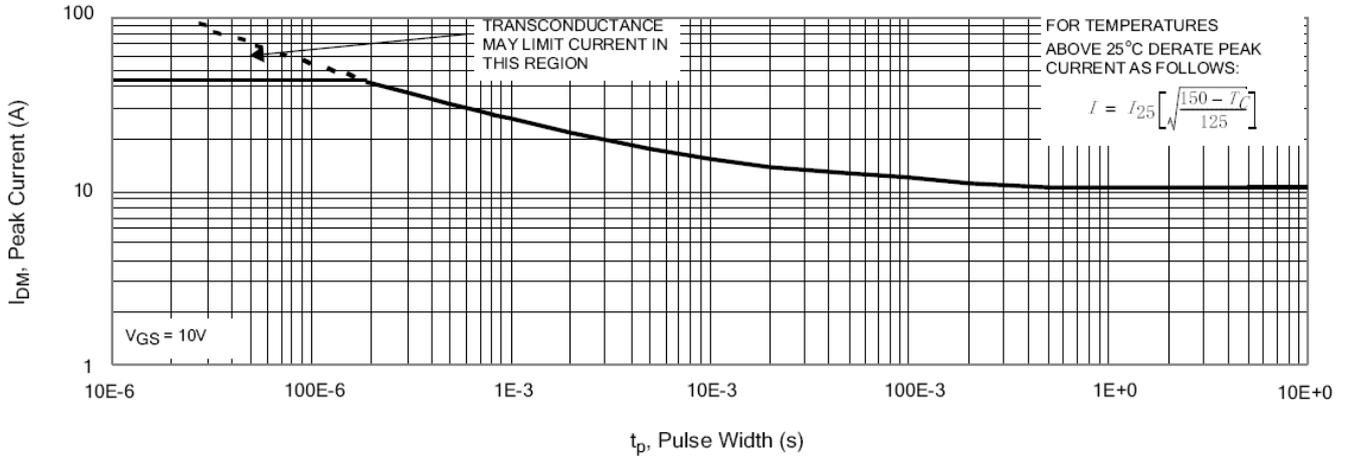


**Figure 5. Typical Drain-to-Source ON Resistance vs Gate Voltage and Drain Current**

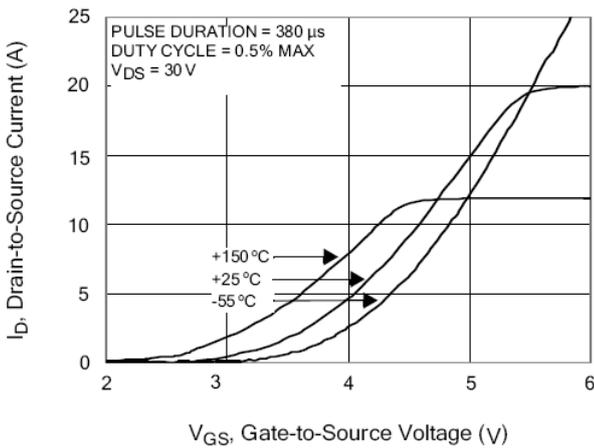


**Typical Characteristics(Cont.)**

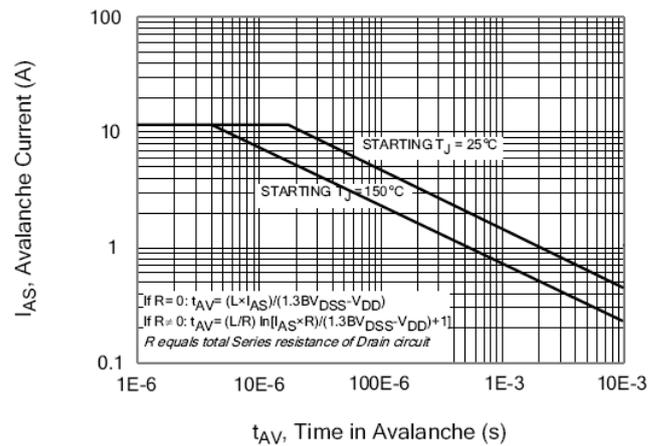
**Figure 6. Maximum Peak Current Capability**



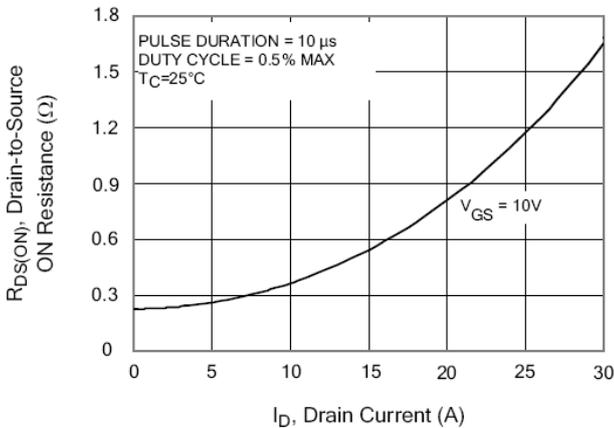
**Figure 7. Typical Transfer Characteristics**



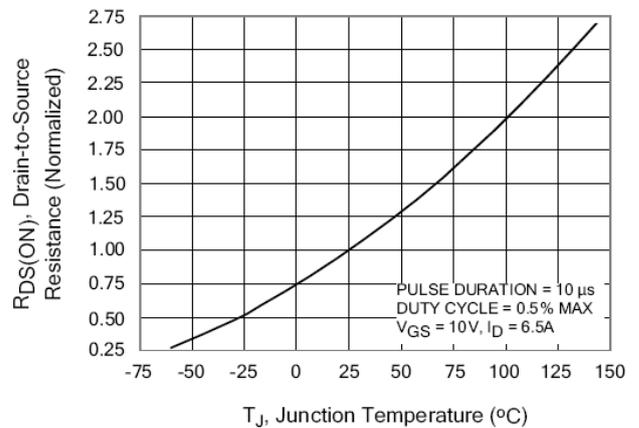
**Figure 8. Unclamped Inductive Switching Capability**



**Figure 9. Typical Drain-to-Source ON Resistance vs Drain Current**

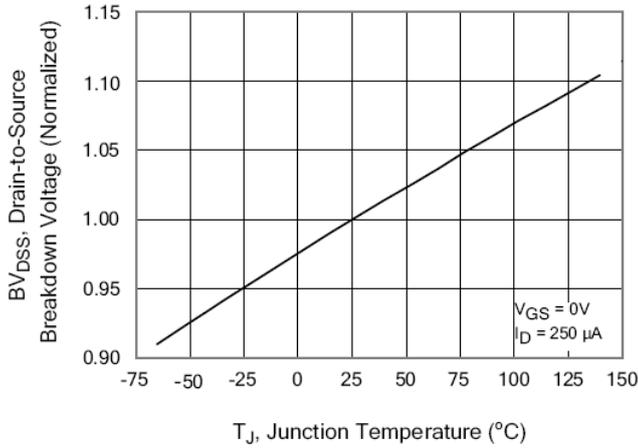


**Figure 10. Typical Drain-to-Source ON Resistance vs Junction Temperature**

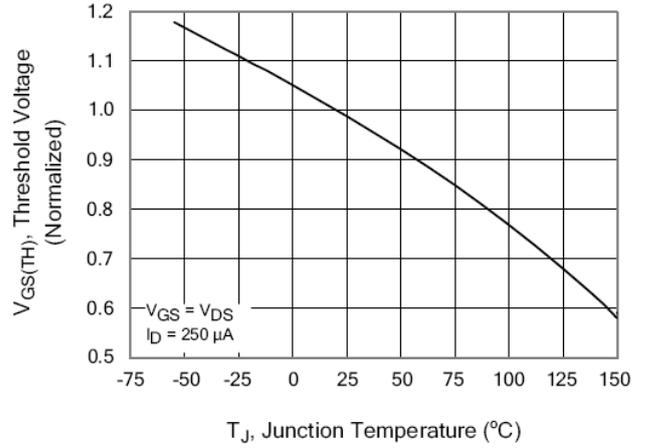


**Typical Characteristics(Cont.)**

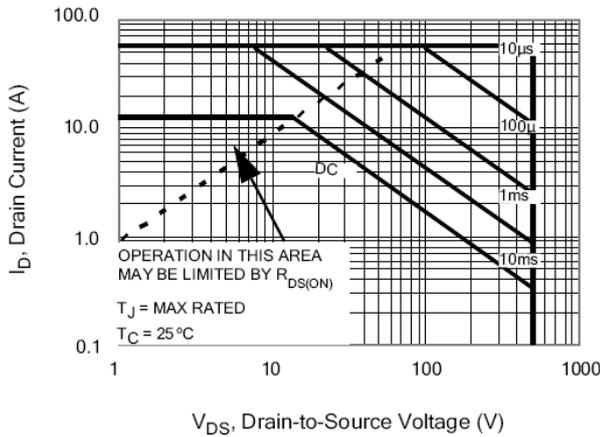
**Figure 11. Typical Breakdown Voltage vs Junction Temperature**



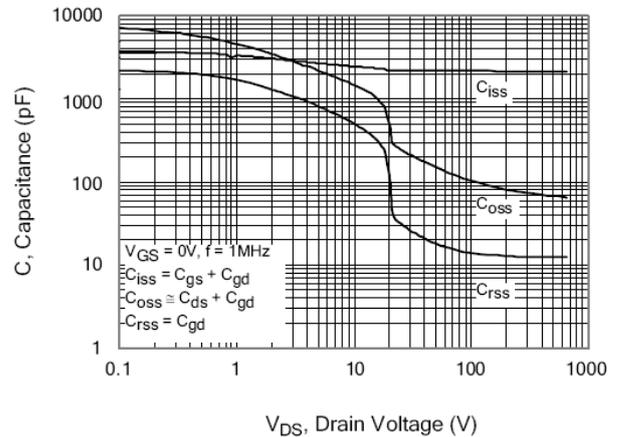
**Figure 12. Typical Threshold Voltage vs Junction Temperature**



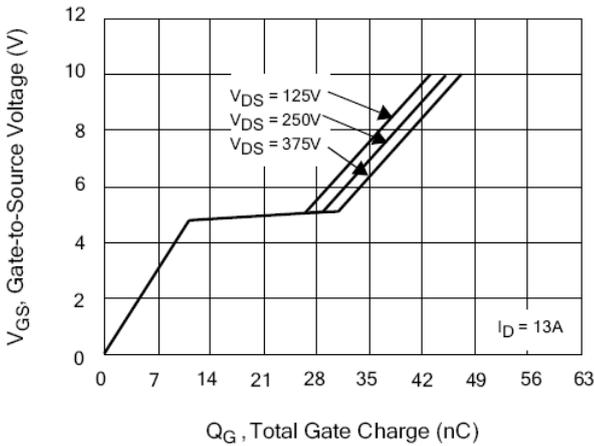
**Figure 13. Maximum Forward Bias Safe Operating Area**



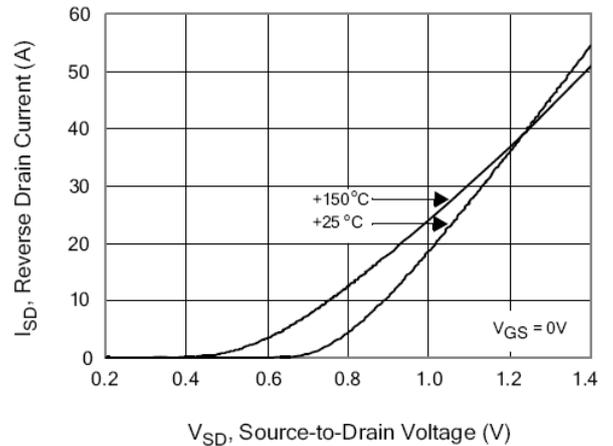
**Figure 14. Typical Capacitance vs Drain-to-Source Voltage**



**Figure 15. Typical Gate Charge vs Gate-to-Source Voltage**



**Figure 16. Typical Body Diode Transfer Characteristics**



**TestCircuitsandWaveforms**

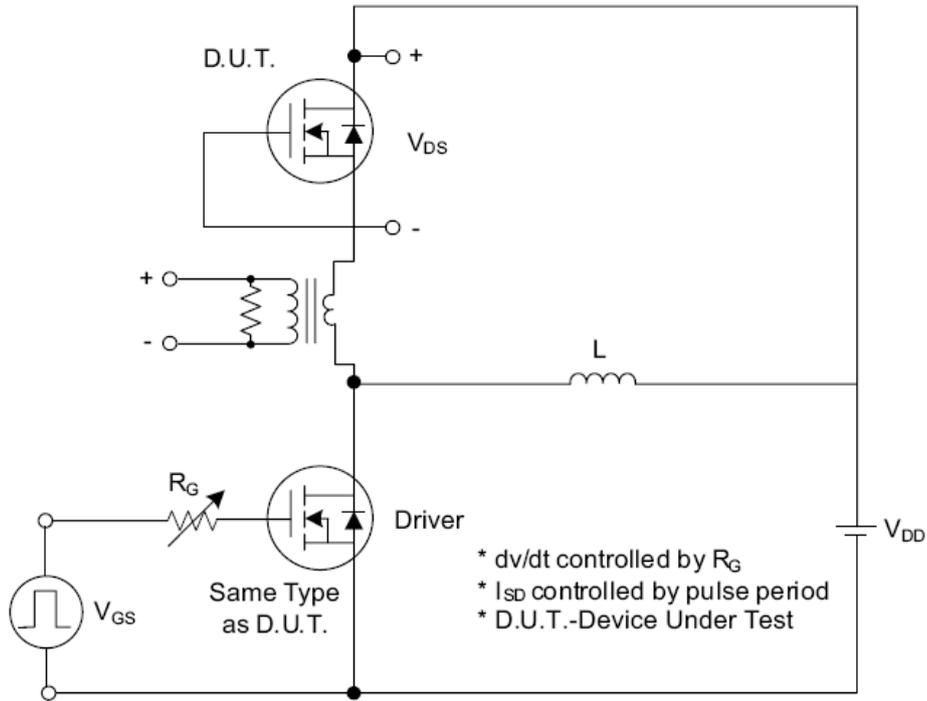


Fig. 1.1 Peak Diode Recovery  $dv/dt$  Test Circuit

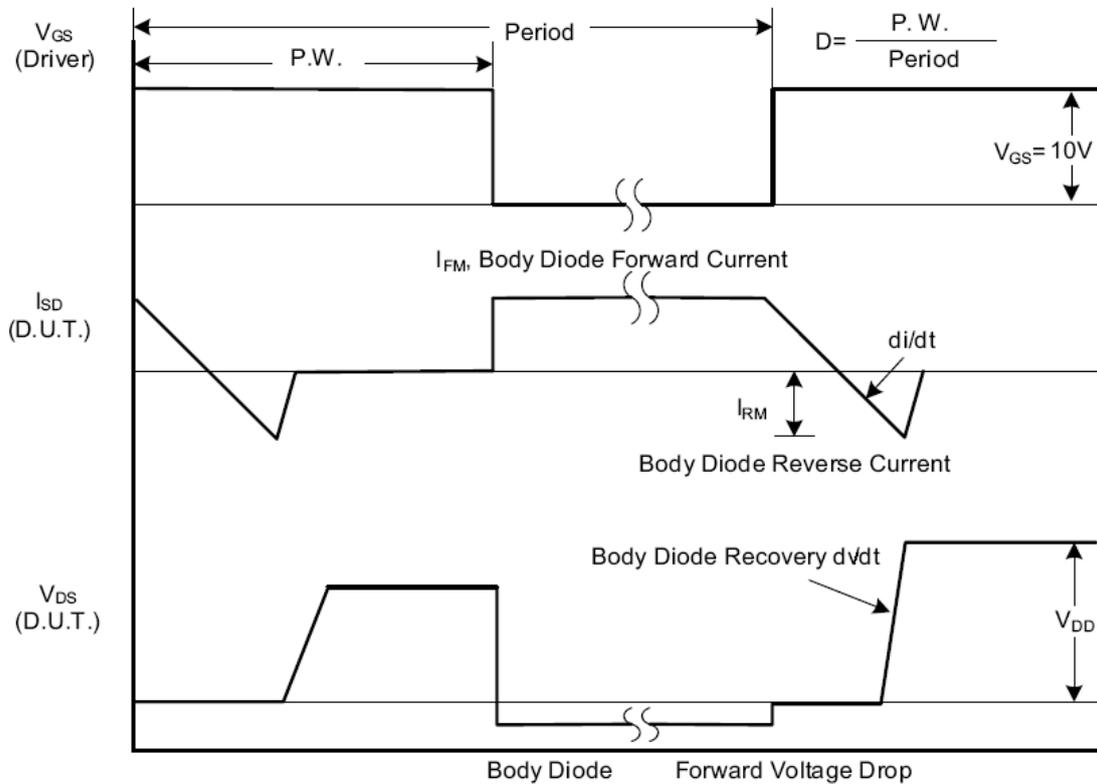


Fig. 1.2 Peak Diode Recovery  $dv/dt$  Waveforms

**Test Circuits and Waveforms (Cont.)**

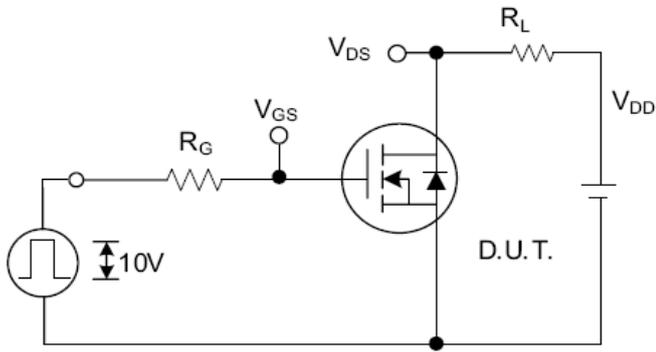


Fig. 2.1 Switching Test Circuit

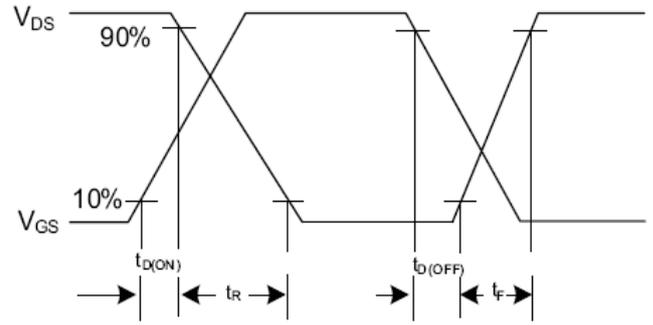


Fig. 2.2 Switching Waveforms

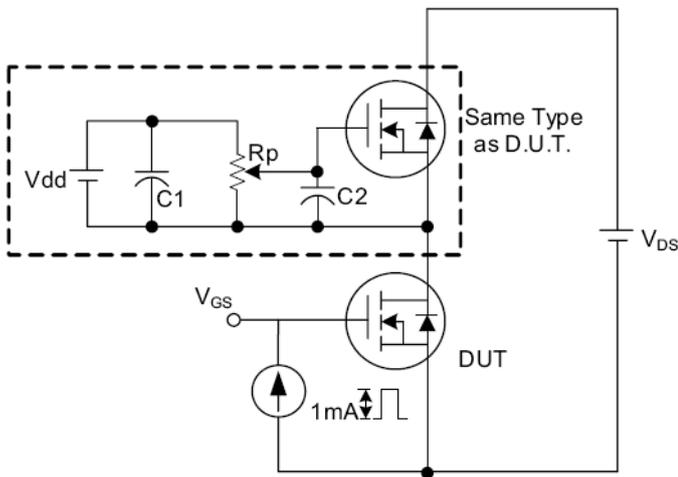


Fig. 3.1 Gate Charge Test Circuit

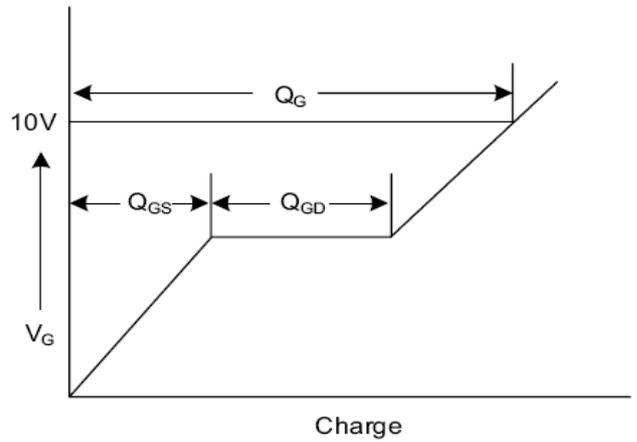


Fig. 3.2 Gate Charge Waveform

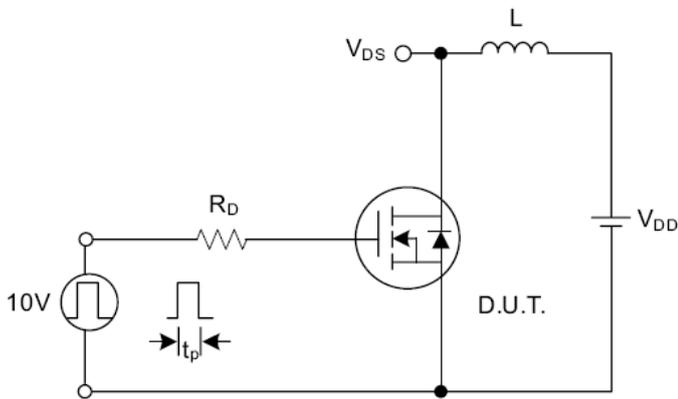


Fig. 4.1 Unclamped Inductive Switching Test Circuit

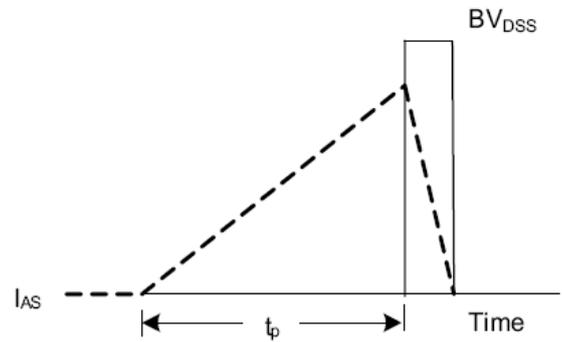
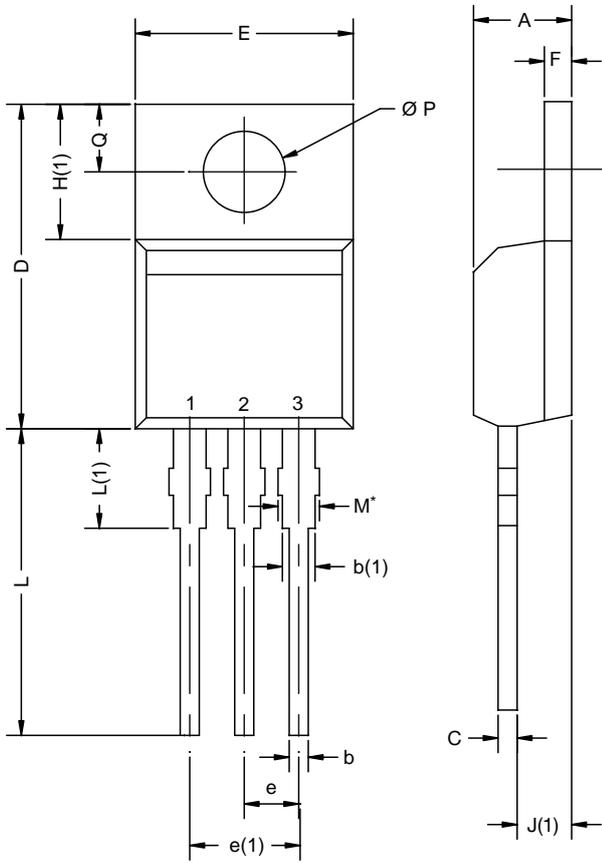


Fig. 4.2 Unclamped Inductive Switching Waveforms

**Package Dimension TO-220**



DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	4.25	4.65	0.167	0.183
b	0.69	1.01	0.027	0.040
b(1)	1.20	1.73	0.047	0.068
c	0.36	0.61	0.014	0.024
D	14.85	15.49	0.585	0.610
E	10.04	10.51	0.395	0.414
e	2.41	2.67	0.095	0.105
e(1)	4.88	5.28	0.192	0.208
F	1.14	1.40	0.045	0.055
H(1)	6.09	6.48	0.240	0.255
J(1)	2.41	2.92	0.095	0.115
L	13.35	14.02	0.526	0.552
L(1)	3.32	3.82	0.131	0.150
Ø P	3.54	3.94	0.139	0.155
Q	2.60	3.00	0.102	0.118

ECN: X12-0208-Rev. N, 08-Oct-12  
DWG: 5471

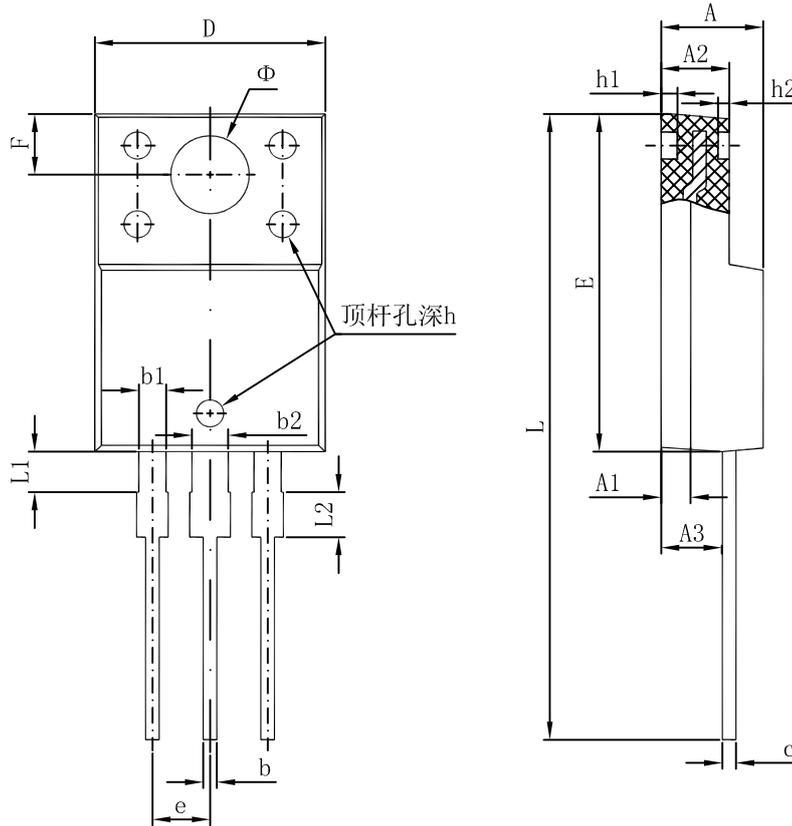
**Notes**

\* M = 1.32 mm to 1.62 mm (dimension including protrusion)  
Heatsink hole for HVM

**REEL SPECIFICATION**

P/N	PKG	QTY
MS13N50P	TO-220	1 tube of 50pcs/1 box of 1000pcs

**Package Dimension TO-220F**



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	4.300	4.700	0.169	0.185
A1	1.300 REF.		0.051 REF.	
A2	2.800	3.200	0.110	0.126
A3	2.500	2.900	0.098	0.114
b	0.500	0.750	0.020	0.030
b1	1.100	1.350	0.043	0.053
b2	1.500	1.750	0.059	0.069
c	0.500	0.750	0.020	0.030
D	9.960	10.360	0.392	0.408
E	14.800	15.200	0.583	0.598
e	2.540 TYP.		0.100 TYP.	
F	2.700 REF.		0.106 REF.	
$\Phi$	3.500 REF.		0.138 REF.	
h	0.000	0.300	0.000	0.012
h1	0.800 REF.		0.031 REF.	
h2	0.500 REF.		0.020 REF.	
L	28.000	28.400	1.102	1.118
L1	1.700	1.900	0.067	0.075
L2	1.900	2.100	0.075	0.083

**REEL SPECIFICATION**

P/N	PKG	QTY
MS13N50F	TO-220F	1 tube of 50pcs/1 box of 1000pcs

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